

## **Training Experience**

Edward G. Bartick

### **External Workshops**

#### **Forensic Raman Spectrometry** – Co-chair with E. Suzuki

American Academy of Forensic Sciences Annual Meeting, Feb. 2001

One-day workshop for fifty students.

#### **Forensic Infrared Spectrometry** – Chair

American Academy of Forensic Sciences Annual Meeting, Feb. 1993

Two-day workshop. Twenty students the first day of lectures and 12 students the second day of laboratory exercises.

#### **Forensic Infrared Spectrometry** – Chair

American Academy of Forensic Sciences Annual Meeting, Feb. 1992

Two-day workshop. Fifty students the first day of lectures and 12 students the second day of laboratory exercises.

#### **Forensic Infrared Spectrometry** - Instructor

Florida State Forensic Laboratory, Orlando – April 1989

I conducted a two and a half-day class with six students.

#### **Forensic Infrared Spectrometry** - Instructor

Virginia State Forensic Laboratory, Roanoke, VA - May 1988

I conducted a two-day class with five students.

#### **Polymer analysis by Infrared Spectrometry** - Clara Craver Organizer

American Chemical Society Fall Meeting Workshop – 1985

Lectured and demonstrated the theory and application of infrared microscopes.

#### **First Molecular Microscopy Short course** - Prof. Jack Katon – Organizer

Miami University, Oxford, OH – June 1985

Lectured on the application of an In-Sample Compartment IR Microscope

#### **Practical Industrial Applications of Infrared Spectroscopy**

Organized by Assist. Prof. John Kokosa

GMI Engineering and Management Institute, Flint, MI – Oct. 1985

I conducted a two-hour lecture on the preparation of samples and the use of sample introduction devices (accessories) for infrared analysis. Attendees learned the optics and theory of using these devices.

#### **Computerized Infrared Spectrometry** - Instructor

ACS 6<sup>th</sup> Biennial Chemical Education Conference – June 1980

Rochester Institute of Technology

I conducted two, two-hour workshops that included a lecture and demonstration to familiarize attendees on the computing capabilities of infrared analysis.